

Notice of References Cited	Application/Control No. 10/517,917		Applicant(s)/Patent Under Reexamination MARTENS ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,764,619 A	06-1998	Nishiuchi et al.	369/275.1
*	B	US-5,981,059 A	11-1999	Bright et al.	428/336
*	C	US-2002/0006105 A1	01-2002	Usami, Yoshihisa	369/275.4
*	D	US-2002/0106475 A1	08-2002	Mihara et al.	428/64.4
*	E	US-2002/0146875 A1	10-2002	Yamaguchi et al.	438/200
*	F	US-2006/0067197 A1	03-2006	Mizushima et al.	369/116
*	G	US-7,166,360 B2	01-2007	Coustet et al.	428/432
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	O					
	P					
	Q					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
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